

Electronic Supplementary information

Relaxation ferroelectric in thin films of Diisopropylammonium Perchlorate

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Synthesis of thin film of Diisopropylammonium Perchlorate

Diisopropylammonium Perchlorate was synthesized by mixing diisopropylamine and perchloric acid in methylalcohol solution with a molar concentration 1:1, and put a drop of Diisopropylammonium Perchlorate on the silicon substrate with a stepped speed (500r/min for 10 seconds and 4000r/min for 50 seconds). Then the films were baked in a 50°C atmosphere for 4 hours before becoming an ideal DIPAP thin film.

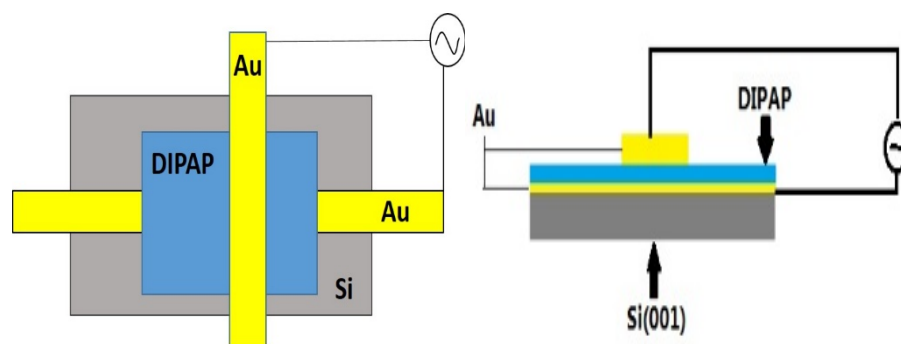


Figure S1. The schematic diagram of the dielectric constant and hysteresis loop measurement

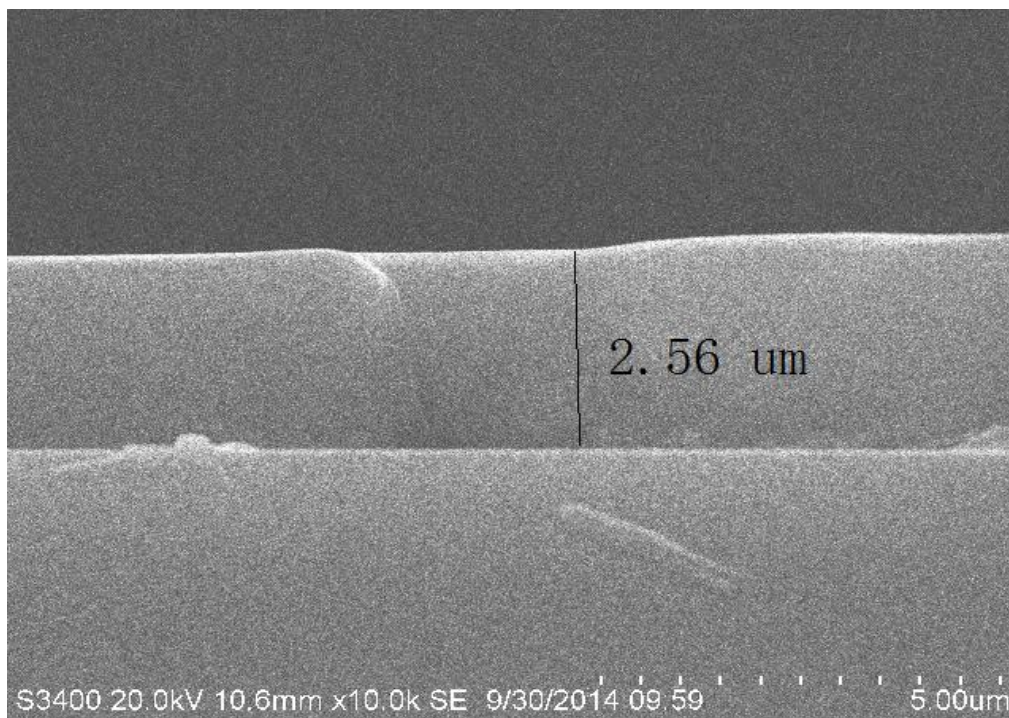


Figure S2. Scanning Electronic Microscopy (SEM) of the film

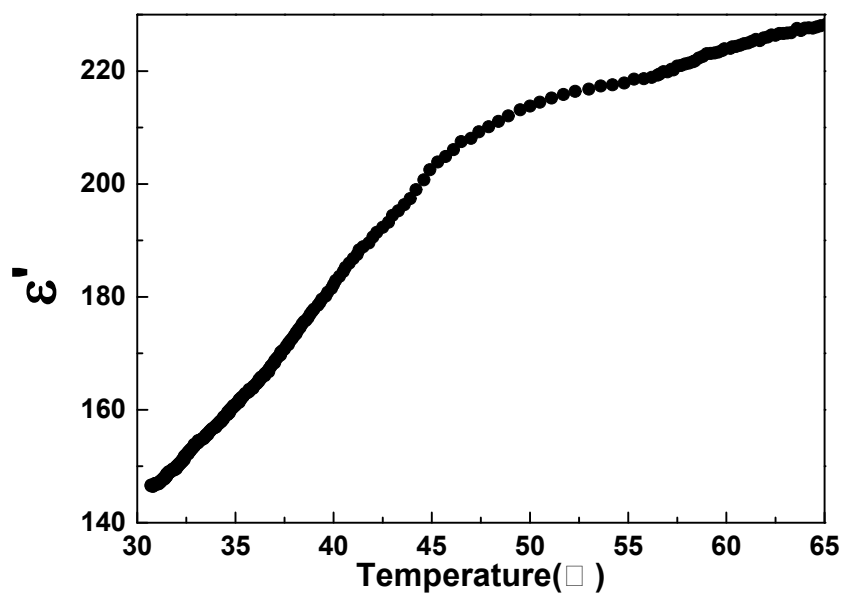


Figure S3. Dielectric measurements in cooling circles at a frequency of 100 kHz.

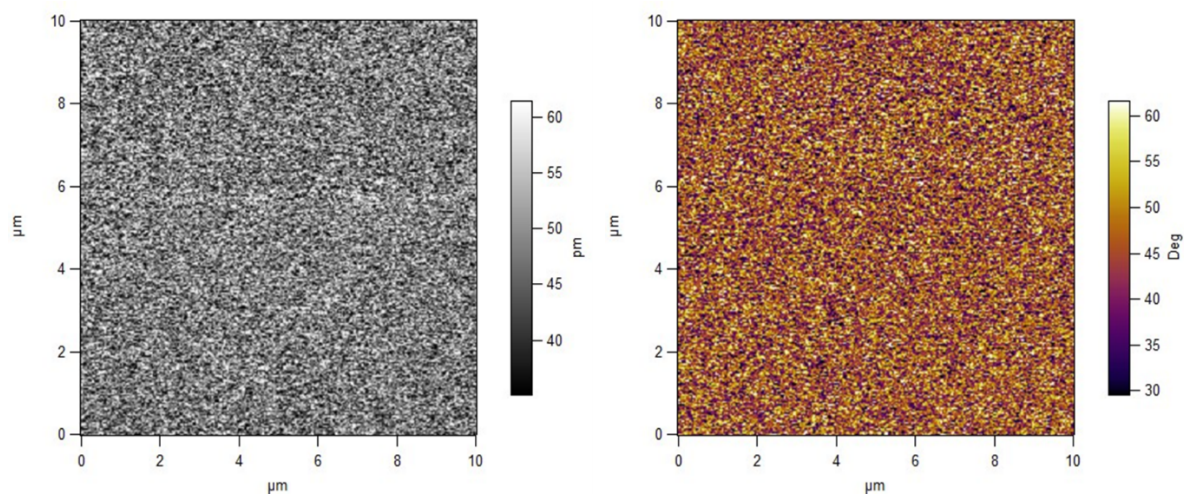


Figure S4. The domain measurements of the films